Product data sheet

1. General description

Silicon Carbide Schottky diode (Bare Die).

2. Features and benefits

- · Extremely fast reverse recovery time
- Low figure of merit (Q_r*V_F)
- · Highly stable switching performance
- Superior in efficiency to Silicon Diode alternatives
- · Reduced losses in associated MOSFET
- Reduced EMI
- · Reduced cooling requirements
- · RoHS compliant

3. Quick reference data

Table 1. Quick reference data

| Symbol | Parameter | Conditions | | Min | Тур | Max | Unit |
|--------------------------|---------------------------------|--|--|-----|-----|------|------|
| V _{RRM} * | repetitive peak reverse voltage | | | - | - | 1200 | V |
| I _{F(AV)} ** | average forward current | δ = 0.5; square-wave pulse | | - | - | 20 | Α |
| Static ch | Static characteristics | | | | | | |
| V _F ** | forward voltage | I _F = 20 A; T _j = 25 °C | | - | 1.5 | 1.8 | V |
| | | I _F = 20 A; T _j = 150 °C | | - | 2.1 | 2.5 | V |
| Dynamic characteristics | | | | | | | |
| Q _r ** | recovered charge | $I_F = 20 \text{ A}$; $V_R = 400 \text{ V}$; $dI_F/dt = 500 \text{ A/}\mu\text{s}$; $T_j = 25 ^{\circ}\text{C}$ | | - | 39 | - | nC |

4. Ordering information

Table 2. Ordering information

| Type number | Orderable part number | Name | Description | Version |
|-------------|-----------------------|-------|-------------------|---------|
| WB20SC120AL | WB20SC120ALZ | Wafer | Bare die on wafer | Die |

5. Limiting values

Table 3. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

| Symbol | Parameter | Conditions | Min | Max | Unit |
|-----------------------|--|--|-----|------|------|
| V _{RRM} * | repetitive peak reverse voltage | | - | 1200 | V |
| V_{RWM}^* | crest working reverse voltage | | - | 1200 | V |
| V_R^* | reverse voltage | DC | - | 1200 | V |
| I _{F(AV)} ** | average forward current | δ = 0.5; square-wave pulse | - | 20 | А |
| I _{FRM} ** | repetitive peak forward current | δ = 0.5; t_p = 25 μs; square-wave pulse | - | 40 | А |
| I _{FSM} ** | non-repetitive peak forward current | t_p = 10 ms; $T_{j(init)}$ = 25 °C; sine-wave pulse | - | 125 | Α |
| | | t_p = 10 μ s; $T_{j(init)}$ = 25 °C; square-wave pulse | - | 1150 | А |
| T _{stg} ** | storage temperature | | -55 | 175 | °C |
| T _j ** | junction temperature | | - | 175 | °C |

6. Characteristics

Table 4. Characteristics

| Symbol | Parameter | Conditions | Min | Тур | Max | Unit |
|-------------------|-------------------|--|-----|-----|-----|------|
| Static cha | racteristics | | | | | |
| V _F * | forward voltage | I _F = 20 A; T _j = 25 °C | - | 1.5 | 1.8 | V |
| V _F ** | forward voltage | I _F = 20 A; T _j = 150 °C | - | 2.1 | 2.5 | V |
| I _R * | reverse current | V _R = 1200 V; T _j = 25 °C | - | 8 | 200 | μA |
| I _R ** | reverse current | V _R = 1200 V; T _j = 150 °C | - | 90 | - | μA |
| Dynamic | characteristics | | ' | | | |
| Q _r ** | recovered charge | $I_F = 20 \text{ A}; V_R = 400 \text{ V}; dI_F/dt = 500 \text{ A}/\mu\text{s};$ $T_j = 25 ^{\circ}\text{C}$ | - | 39 | - | nC |
| C _d ** | diode capacitance | f = 1 MHz; V _R = 1 V; T _j = 25 °C | - | 845 | - | pF |
| | | f = 1 MHz; V _R = 400 V; T _j = 25 °C | - | 79 | - | pF |
| | | f = 1 MHz; V _R = 800 V; T _j = 25 °C | - | 58 | - | pF |

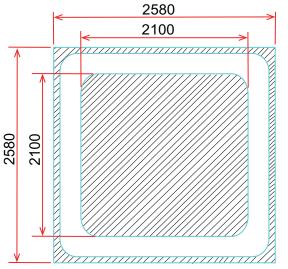
Notes:

^{(1) *} mean that parameter are 100% test at T_{amb} = 25°C

^{(2) **} means that the guaranteed ratings and parameter limits will depend on the assembled structure. When correctly assembled with suitable die bonding and wire bonding, the device will have ratings and characteristics guaranteed in this data sheet, similar to the assembled devices like WNSC2D201200W.

| MECHANICAL PATAMETER | | |
|------------------------------|--------------------------|-----------------|
| Chip size | 2.58 x 2.58 | mm ² |
| Anode pad size | 2.1 x 2.1 | mm ² |
| Scribe line width | 80 | μm |
| Area total / active | 6.66 / 4.41 | mm ² |
| Thickness | 165 | μm |
| Wafer size | 100 | mm |
| Max possible chips per wafer | 1063 | pcs |
| Passivation | Polyimide | |
| Front metal | AlCu (4µm) | |
| Back metal | Ti Ni Ag (0.2/0.3/2.0μm) | |

CHIP LAYOUT



7. Legal information

Data sheet status

| Document status [1][2] | Product status [3] | Definition |
|--------------------------------------|--------------------|---|
| Objective [short] data sheet | Development | This document contains data from the objective specification for product development. |
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WeEn Semiconductors WB20SC120AL

Silicon Carbide Schottky diode - Bare Die

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